

Data sheet acquired from Harris Semiconductor

CMOS Dual 'D'-Type Flip-Flop

High-Voltage Types (20-Volt Rating)

■ CD40138 consists of two identical, independent data-type flip-flops. Each flipflop has independent data, set, reset, and clock inputs and Q and Q outputs. These devices can be used for shift register applications, and, by connecting Q output to the data input, for counter and toggle applications. The logic level present at the D input is transferred to the Q output during the positive-going transition of the clock pulse. Setting or resetting is independent of the clock and is accomplished by a high level on the set or reset line, respectively.

The CD4013B types are supplied in 14-lead hermetic dual-in-line ceramic packages (D and F suffixes), 14-lead dual-in-line plastic packages (E suffix), and in chip form (H suffix).

RECOMMENDED OPERATING CONDITIONS

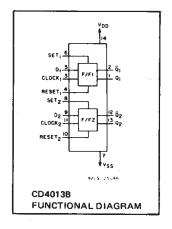
CD4013B Types

Features:

- Set-Reset capability
- Static flip-flop operation retains state indefinitely with clock level either "high" or "low"
- Medium-speed operation 16 MHz (typ.) clock toggle rate at 10V
- Standardized symmetrical output characteristics
- 100% tested for quiescent current at 20 V
- Maximum input current of 1 µA at 18 V over full package temperature range; 100 nA at 18 V and 25°C
- Noise margin (over full package temperature range): 1 V at V_{DD}=5 V 2 V at V_{DD}=10 V 2.5 V at V_{DD}=15 V
- 5-V, 10-V, and 15-V parametric ratings
- Meets all requirements of JEDEC Tentative Standard No. 13B, "Standard Specifications for Description of 'B' Series CMOS Devices"

Applications:

Registers, counters, control circuits



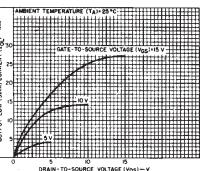


Fig. 1 - Typical output low (sink) current characteristics.

DRAIN-TO-SOURCE VOLTAGE (VDS)-V

At $T_A = 25^{\circ}$ C, Except as Noted. For maximum reliability, nominal operating conditions should be selected so that operation is always within the following ranges:

CHARACTERISTIC	V _{DD}	Li	UNITS		
	(V)	MIN.	MAX.]	
Supply-Voltage Range (For T _A = Full Package Temperature Range)	_	3	18	V	
Data Setup Time t _S	5	40	_	İ	
	10	20	-	ns	
	15	15	_		
Clock Pulse Width t _W	5	140	-		
	10	60	_	ns	
	15	40			
	5		3.5		
Clock Input Frequency fCL	10	dc	8	MHz	
	15		12		
Clock Rise or Fall Time t _r CL,* t _f CL	5	_	500		
	10	-	30	μς	
	15	_	6		
Set or Reset Pulse Width	5	180	_		
	10	80	_	ns	
^t W	15	50	-		

^{*}If more than one unit is cascaded in a parallel clocked operation, t_rCL should be made less than or equal to the sum of the fixed propagation delay time at 15 pF and the transition time of the output driving stage for the estimated capacitive load.

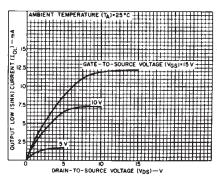


Fig. 2 - Minimum output low (sink) current characteristics.

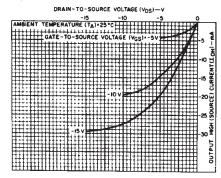


Fig. 3 - Typical output high (source) current characteristics.

CD4013B Types

STATIC ELECTRICAL CHARACTERISTICS

CHARAC- TERISTIC	CONDITIONS LIMITS AT INDICATED TEMPERATURES (°C))C)	UNITS			
]	Vo	VIN	V_{DD}						+25		
	(V)	(V)	(V)	55	-4 0	+85	+125	Min.	Тур.	Max.	
Quiescent		0,5	5	1	1	30	30	_	0.02	1	
Device		0,10	10	2	2	60	60		0.02	2	μА
Current	_	0,15	15	4	4	120	120	_	0.02	4	M^
I _{DD} Max.	_	0,20	20	20	20	600	600	-	0.04	20	
Output Low											
(Sink)	0.4	0,5	5	0.64	0.61	0.42	0.36	0.51	1	_	
Current,	0.5	0,10	10	1.6	1.5	1.1	0.9	1.3	2.6	_	
IOL Min.	1.5	0,15	15	4.2	4	2.8	2.4	3.4	6.8	-	mA
Output High	4.6	0,5	5	-0.64	-0.61	-0.42	-0.36		-1	_	I IIIA
(Source)	2.5	0,5	5	-2	-1.8	-1.3	-1.15	-1.6	-3.2	_	
Current,	9.5	0,10	10	-1.6	-1.5	-1.1	-0.9	-1.3	-2.6	_	
IOH Min.	13.5	0,15	15	-4.2	-4	-2.8	-2.4	-3.4	-6.8	_	
Output Volt- age:	_	0.5	5		0.0	15		_	0	0.05	
Low-Level		0,10	10					<u> </u>	0	0.05	
VOL Max.	_	0,15	15		0.05 0.05			0	0.05	1	
										0.00	V
Output Volt-		0,5	5		4.9)E		4.95	5		ľ
age: High-Level,		0,10	10		9.9			9.95	10	 -	
V _{OH} Min.		0,10	15		14.	_		14.95	15	_	
								14.55	15		
Input Low	0.5,4.5	_	5		1.			_	-	1.5	
Voltage,	1,9	_	10		3					3	
VIL Max.	1.5,13.5	_	15		4			_		4	v
Input High	0.5,4.5	_	5		3.	5		3.5	_		·
Voltage,	1,9		10	7			7		_		
V _{IH} Min.	1.5,13.5	-	15		1	1		11	-	-	
Input Current, I _{IN} Max.	_	0,18	18	±0.1	±0.1	±1	±1	-	±10-5	±0.1	μΑ

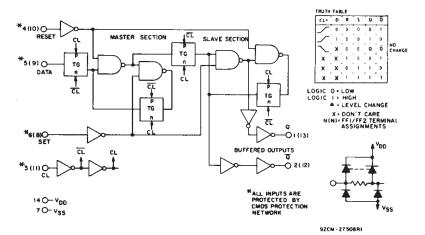


Fig. 7 - Logic diagram and truth table for CD4013B (one of two identical flip-flops).

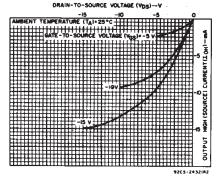


Fig. 4 — Minimum output high (source) current characteristics.

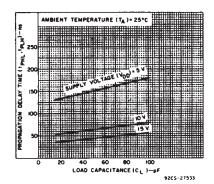


Fig. 5 — Typical propagation delay time vs. load capacitance (CLOCK or SET to O,CLOCK or RESET to \overline{\overline{O}}.

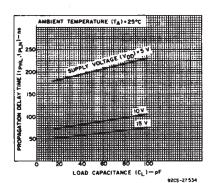
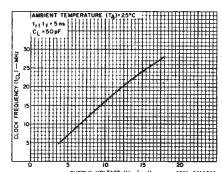


Fig. 6 — Typical propagation delay time vs. load capacitance (SET to \overline{Q} or RESET to Q.



SUPPLY VOLTAGE (VOC!--V 92C5-26392R2

Fig. 8 — Typical maximum clock frequency vs.

supply voltage.

CD4013B Types

MAXIMUM RATINGS, Absolute-Maximum Values:	
DC SUPPLY-VOLTAGE RANGE, (V _{DD}) Voltages referenced to V _{SS} Terminal)	-0.5V to 1.20V
INPUT VOLTAGE RANGE, ALL INPUTS	
DC INPUT CURRENT, ANY ONE INPUT	±10mA
POWER DISSIPATION PER PACKAGE (PD): For T _A = -55°C to +100°C	500mW
For T _A = +100°C to +125°C Derate Linearit	y at 12mW/°C to 200mW
DEVICE DISSIPATION PER OUTPUT TRANSISTOR FOR TA = FULL PACKAGE-TEMPERATURE RANGE (All Package Types)	100mW
OPERATING-TEMPERATURE RANGE (TA)	
STORAGE TEMPERATURE RANGE (Tstg)	
LEAD TEMPERATURE (DURING SOLDERING): At distance 1/16 ± 1/32 inch (1.59 ± 0.79mm) from case for 10s max	+265°C

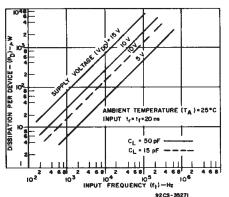


Fig. 9 – Typical power dissipation vs. frequency.

DYNAMIC ELECTRICAL CHARACTERISTICS

At T_A = 25°C; Input t_t , t_t = 20 ns, C_L = 50 pF, R_L = 20 k Ω

CHARACTERISTIC	TEST CONDITIONS		LIMITS			
CHARACTERISTIC	V _{DD} (V)	MIN. TYP.		MAX.	UNITS	
Propagation Delay Time:	5		150	300	1.48	
Clock to Q or Q Outputs	10	-	65	130	ns	
t _{PHL} , t _{PLH}	15		45	90		
	5	_	150	300		
Set to Q or Reset to Q tplH	10	-	65	130	ns	
	15	-	45	90		
	5		200	400		
Set to Q or Reset to Q tPHL	10		85	170	ns	
	15	_	60	120	, a	
	5	_	100	200		
Transition Time tthi, ttlh	10	_	50	100	ns	
	15	_	40	80		
Maximum Clock Input	5	3.5	7	1 -		
Frequency# fcL	10	8	16	_	MHz	
	15	12	24	_		
	5	_	70	140		
Minimum Clock Pulse Width	10	_	30	60	ns	
tw	15	_ 4	20	40		
Minimum Set or Reset Pulse	5		90	180	7	
Width tw	10		40	80	ns	
	15	_	25	50		
	5	_	20	40		
Minimum Data Setup Time ts	10	_	10	20	ns	
	15	_	7	15	1	
	5		2	5		
Minimum Data Hold Time t _H	10	_	2	5	ns	
	15	—	2	5	1	
Clock Input Rise or Fall Time	5		_	500		
trCL, trCL	10	_	–	30	μs	
	15	_	_	6		
Input Capacitance CiN	Any Input		5	7.5	pF	

[#]Input $t_r, t_f = 5$ ns.

TEST CIRCUITS

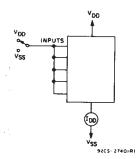


Fig. 10 - Quiescent device current.

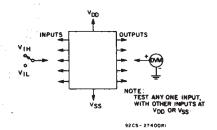


Fig. 11 - Input voltage.

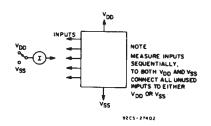
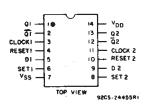


Fig. 12 - Input current.

CD4013B Types



TERMINAL ASSIGNMENT

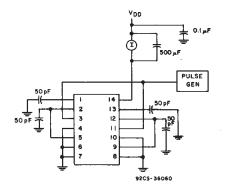
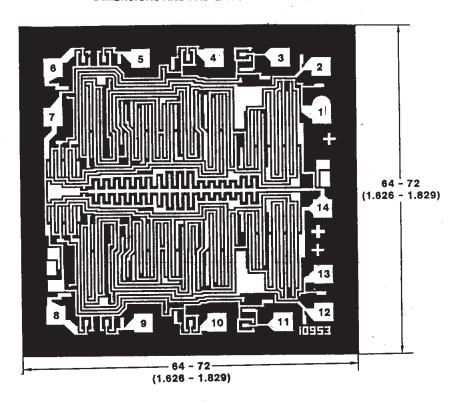


Fig. 13—Dynamic power dissipation test circuit.

DIMENSIONS AND PAD LAYOUT FOR CD4013BH



Dimensions in parentheses are in millimeters and are derived from the basic inch dimensions as indicated. Grid graduations are in mils $(10^{-3} \, \text{inch})$.

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